

November 2009

ISL9V5036S3S / ISL9V5036P3 / ISL9V5036S3

EcoSPARK® 500mJ, 360V, N-Channel Ignition IGBT

General Description

The ISL9V5036S3S, ISL9V5036P3, and ISL9V5036S3 are the next generation IGBTs that offer outstanding SCIS capability in the D²-Pak (TO-263) and TO-220 plastic package. These devices are intended for use in automotive ignition circuits, specifically as coil drivers. Internal diodes provide voltage clamping without the need for external components.

EcoSPARK® devices can be custom made to specific clamp voltages. Contact your nearest Fairchild sales office for more information.

Formerly Developmental Type 49443

Applications

- Automotive Ignition Coil Driver Circuits
- · Coil-On Plug Applications

Features

- Industry Standard D²-Pak package
- SCIS Energy = 500mJ at T_J = 25°C
- · Logic Level Gate Drive
- Qualified to AEC Q101
- RoHS Compliant



Package Symbol JEDEC TO-263AB JEDEC TO-220AB JEDEC TO-262AA D2-Pak COLLECTOR GATE COLLECTOR (FLANGE) COLLECTOR (FLANGE)

Device Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
BV _{CER}	Collector to Emitter Breakdown Voltage (I _C = 1 mA)	390	V	
BV _{ECS}	Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	24	V	
E _{SCIS25}	At Starting $T_J = 25$ °C, $I_{SCIS} = 38.5A$, $L = 670 \mu Hy$	500	mJ	
E _{SCIS150}	At Starting $T_J = 150$ °C, $I_{SCIS} = 30$ A, $L = 670 \mu$ Hy	300	mJ	
I _{C25}	Collector Current Continuous, At T _C = 25°C, See Fig 9	46	Α	
I _{C110}	Collector Current Continuous, At T _C = 110°C, See Fig 9	31	Α	
V_{GEM}	Gate to Emitter Voltage Continuous	±10	V	
P _D	Power Dissipation Total T _C = 25°C	250	W	
	Power Dissipation Derating T _C > 25°C	1.67	W/°C	
TJ	Operating Junction Temperature Range	-40 to 175	°C	
T _{STG}	Storage Junction Temperature Range	-40 to 175	°C	
TL	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C	
T _{pkg}	Max Lead Temp for Soldering (Package Body for 10s)		°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω	4	kV	

Device Marking		Device		Package	Reel Size		Tape Width		Quantity
V5036S		ISL9V5036S3ST		TO-263AB	330mm		24mm		800
V5036P		ISL9V5036P3		TO-220AA	Tube		N/A		50
V5036S		ISL9V5036S3		TO-262AA	Tube		N/A		50
V50	36S	ISL9V5036S3S		TO-263AB	Tube		N/A		50
lectric	al Chara	acteristics T _A = 25°	°C unl	ess otherwise n	oted				
Symbol	Parameter			Test Con	Min	Тур	Max	Units	
ff State	Characte	ristics							
BV _{CER}	Collector to Emitter Breakdown Voltage			$I_C = 2mA$, V_{GE} $R_G = 1K\Omega$, See $T_J = -40$ to 150	330	360	390	V	
BV _{CES}	Collector to Emitter Breakdown Voltage			I _C = 10mA, V _{GE} = 0, R _G = 0, See Fig. 15 T _J = -40 to 150℃		360	390	420	V
BV _{ECS}	Emitter to Collector Breakdown Voltage			$I_C = -75$ mA, $V_{GE} = 0$ V, $T_C = 25$ °C		30	-	-	V
BV_GES	Gate to Emitter Breakdown Voltage			$I_{GES} = \pm 2mA$	±12	±14	_	V	
I _{CER}	Collector to	o Emitter Leakage Currer	nt	V _{CER} = 250V,	$T_C = 25^{\circ}C$	-	-	25	μA
				$R_G = 1K\Omega$, See Fig. 11	T _C = 150°C	-	-	1	mA
I _{ECS}	Emitter to	Collector Leakage Currer	nt	$V_{EC} = 24V$, See		-	-	1	mA
				Fig. 11	$T_C = 150$ °C	-	-	40	mA
R ₁	Series Gate Resistance Gate to Emitter Resistance					-	75	-	Ω
R ₂ In State	Characte				<u> </u>	10K	-	30K	Ω
V _{CE(SAT)}	Collector to Emitter Saturation Voltage		age	I _C = 10A, V _{GE} = 4.0V	T _C = 25°C, See Fig. 4	-	1.17	1.60	V
V _{CE(SAT)}	Collector to Emitter Saturation Voltage		age	$I_{C} = 15A,$ $V_{GE} = 4.5V$	$T_C = 150^{\circ}C$	-	1.50	1.80	V
ynamic	Characte	ristics		GL -			ı		
Q _{G(ON)}	Gate Charge			I _C = 10A, V _{CE} = 12V, V _{GE} = 5V, See Fig. 14		-	32	-	nC
V _{GE(TH)}	Gate to Er	mitter Threshold Voltage		$I_C = 1.0 \text{mA},$	T _C = 25°C	1.3	-	2.2	V
(,				V _{CE} = V _{GE,} See Fig. 10	T _C = 150°C	0.75	-	1.8	V
V_{GEP}	Gate to Er	nitter Plateau Voltage		$I_C = 10A$,	$V_{CE} = 12V$	-	3.0	-	V
witching	Charact	eristics							
t _{d(ON)R}	Current Turn-On Delay Time-Resistive			$V_{CF} = 14V, R_1 = 1\Omega,$		-	0.7	4	μs
t _{rR}	Current Rise Time-Resistive		$V_{GE} = 5V$, $R_G = 1K\Omega$ $T_J = 25^{\circ}C$, See Fig. 12		-	2.1	7	μs	
t _{d(OFF)L}	Current Turn-Off Delay Time-Inductive		V _{CE} = 300V, L = 2mH,		-	10.8	15	μs	
t _{fL}	Current Fall Time-Inductive			$V_{GE} = 5V$, $R_G = 1K\Omega$ $T_J = 25$ °C, See Fig. 12		-	2.8	15	μs
SCIS	Self Clamped Inductive Switching			T_J = 25°C, L = 670 μH, R_G = 1KΩ, V_{GE} = 5V, See Fig. 1 & 2		-	-	500	mJ

TO-263, TO-220, TO-262

Thermal Resistance Junction-Case

 $\mathsf{R}_{\underline{\theta}\mathsf{JC}}$

0.6

°C/W

Typical Characteristics

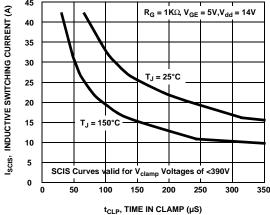


Figure 1. Self Clamped Inductive Switching
Current vs Time in Clamp

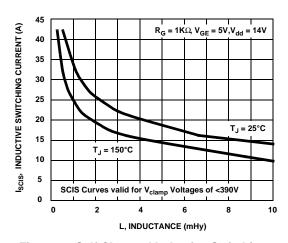


Figure 2. Self Clamped Inductive Switching Current vs Inductance

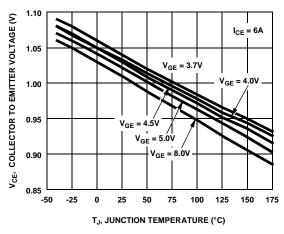


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

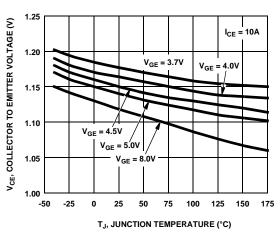


Figure 4.Collector to Emitter On-State Voltage vs Junction Temperature

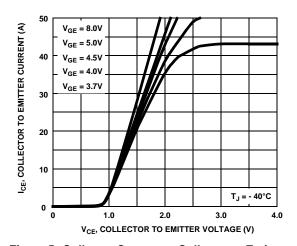


Figure 5. Collector Current vs Collector to Emitter On-State Voltage

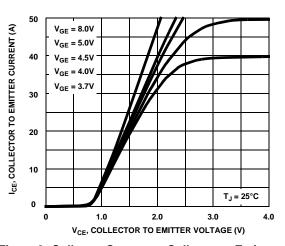


Figure 6. Collector Current vs Collector to Emitter On-State Voltage

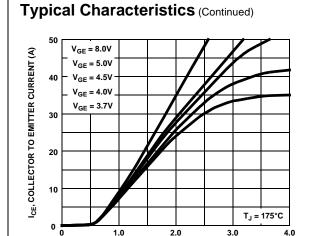


Figure 7. Collector to Emitter On-State Voltage vs Collector Current

V_{CE}, COLLECTOR TO EMITTER VOLTAGE (V)

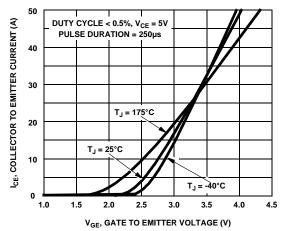


Figure 8. Transfer Characteristics

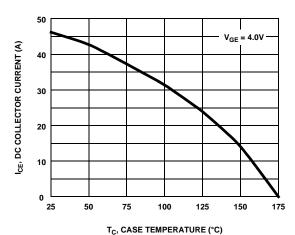


Figure 9. DC Collector Current vs Case Temperature

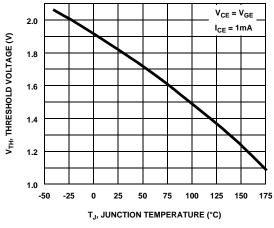


Figure 10. Threshold Voltage vs Junction Temperature

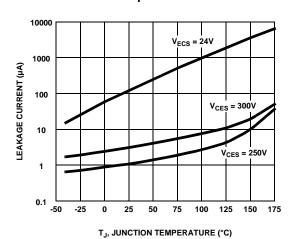


Figure 11. Leakage Current vs Junction Temperature

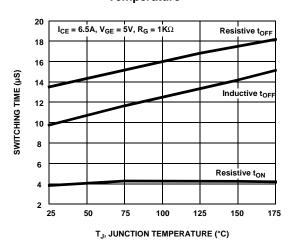
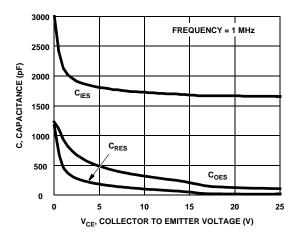


Figure 12. Switching Time vs Junction Temperature

Typical Characteristics (Continued)



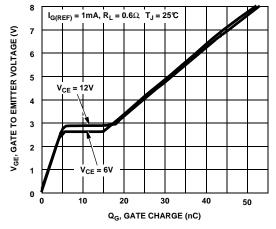


Figure 13. Capacitance vs Collector to Emitter Voltage

Figure 14. Gate Charge

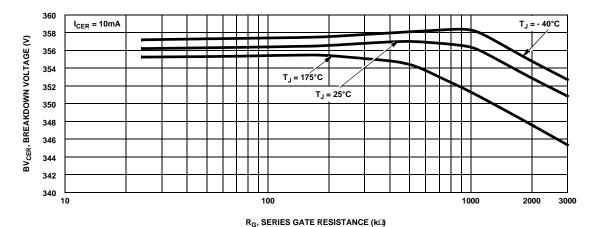


Figure 15. Breakdown Voltage vs Series Gate Resistance

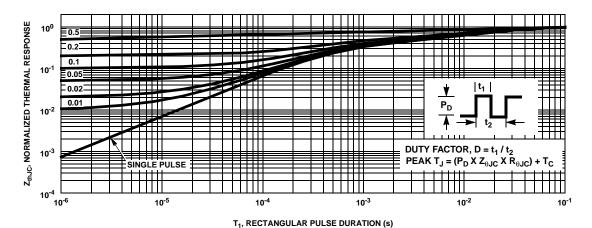
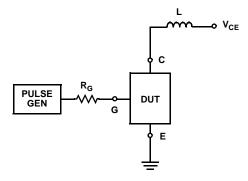


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuits and Waveforms



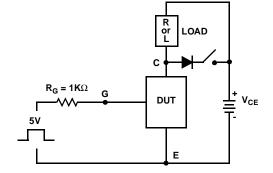


Figure 17. Inductive Switching Test Circuit

Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

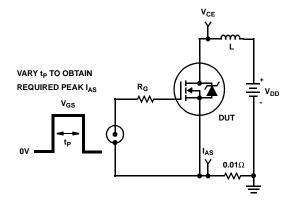


Figure 19. Energy Test Circuit

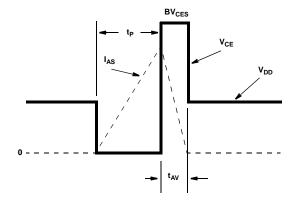


Figure 20. Energy Waveforms

SPICE Thermal Model JUNCTION REV 1 May 2002 ISL9V5036S3S / ISL9V3536P3 / ISL9V5036S3 CTHERM1 th 6 4.0e2 CTHERM2 6 5 3.6e-3 CTHERM3 5 4 4.9e-2 RTHERM1 CTHERM1 CTHERM4 4 3 3.2e-1 CTHERM5 3 2 3.0e-1 CTHERM6 2 tl 1.6e-2 6 RTHERM1 th 6 1.0e-2 RTHERM2 6 5 1.4e-1 RTHERM3 5 4 1.0e-1 RTHERM2 CTHERM2 RTHERM4 4 3 9.0e-2 RTHERM5 3 2 9.4e-2 RTHERM6 2 tl 1.9e-2 5 SABER Thermal Model SABER thermal model ISL9V5036S3S / ISL9V5036P3 / ISL9V5036S3 RTHERM3 CTHERM3 template thermal_model th tl thermal_c th, tl ctherm.ctherm1 th 6 = 4.0e2ctherm.ctherm2 65 = 3.6e-3ctherm.ctherm3 5 4 = 4.9e-2ctherm.ctherm4 43 = 3.2e-1RTHERM4 CTHERM4 ctherm.ctherm5 3 2 = 3.0e-1 ctherm.ctherm6 2 tl = 1.6e-2 rtherm.rtherm1 th 6 = 1.0e-2 3 rtherm.rtherm2 6 5 = 1.4e-1 rtherm.rtherm3 5 4 = 1.0e-1 rtherm.rtherm4 4 3 = 9.0e-2RTHERM5 CTHERM5 rtherm.rtherm5 3 2 = 9.4e-2rtherm.rtherm6 2 tl = 1.9e-2 2 RTHERM6 CTHERM6 CASE





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SuperSOT™-6
SuperSOT™-8
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TinyPower™
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TinyWir™
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